Test Report No:
2670309R-RFJPV02S-A

TEST REPORT
Japan Rules & Regulations

Product Name	CHARGING DOCK
Brand Name	ASUS
Model No.	P728DOCK
Applicant´s Name / Address	ASUSTeK COMPUTER INC. 1F., No. 15, Lide Rd., Beitou Dist., Taipei City 112, Taiwan
Manufacturer's Name	ASUSTeK COMPUTER INC.
Test Method Requested, Standard	MIC Notice No.88 Appendix No.43 Item 19 of Article 2 Paragraph 1
Verdict Summary	IN COMPLIANCE
Documented by Jinn Chen	Jinn Chen
Approved by Alan Chen	Alan Chen
Date of Receipt	2026/07/13
Date of Issue	2026/08/24
Report Version	V1.0

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Competences and Guarantees

DEKRA is a testing laboratory competent to carry out the tests described in this report.
In order to assure the traceability to other national and international laboratories, DEKRA has a calibration and maintenance program for its measurement equipment.

DEKRA guarantees the reliability of the data presented in this report, which is the result of the measurements and the tests performed to the item under test on the date and under the conditions stated in the report and it is based on the knowledge and technical facilities available at DEKRA at the time of performance of the test.

DEKRA is liable to the client for the maintenance of the confidentiality of all information related to the item under test and the results of the test.

The results presented in this Test Report apply only to the particular item under test established in this document.

IMPORTANT: No parts of this report may be reproduced or quoted out of context, in any form or by any means, except in full, without the previous written permission of DEKRA.

General Conditions

1. The test results relate only to the samples tested.
2. The test results shown in the test report are traceable to the national/international standard through the calibration report of the equipment and evaluated measurement uncertainty herein.
3. This report must not be used to claim product endorsement by TAF or any agency of the government.
4. The test report shall not be reproduced without the written approval of DEKRA Testing and Certification Co., Ltd.
5. Measurement uncertainties evaluated for each testing system and associated connections are given here to provide the system information for reference. Compliance determinations do not take into account measurement uncertainties for each testing system, but are based on the results of the compliance measurement.

Revision History

Version	Description	Issued Date
V1.0	Initial issue of report	2026/08/24

Summary of Test Result

Report Clause	Test Items	Result (PASS/FAIL)	Remark
3	Antenna Power, Antenna Power Tolerance and E.I.R.P	PASS	-
4	Occupied Bandwidth	PASS	-
5	Frequency Tolerance	PASS	-
6	Unwanted Emission Strength	PASS	-
7	Secondary Radiated Emission Strength	PASS	-
8	Interference Prevention Function	PASS	-

Comments and Explanations
The declared of product specification for EUT presented in the report are provided by the manufacturer, and the manufacturer takes all the responsibilities for the accuracy of product specification.

1. General Information

1.1. EUT Description

Frequency Band	2400 ~ 2483.5 MHz	
Operating Frequency	2402 ~ 2480 MHz	
Channel Number	40 Channels	
Mode	2.4 GHz Wireless	
Type of Modulation	GFSK (1 Mbps / 2 Mbps)	
Declared Antenna Power	GFSK (1 Mbps)	3.1477 mW
	GFSK (2 Mbps)	3.2211 mW

Accessories Information		
No.	Equipment Name	Description
1	USB TO USB C Cable	Shielded, 2m

Antenna Information				
No.	Brand Name	Part No.	Type	Gain (dBi)
1	Dongguan Yirui Electronic Technology Co., Ltd.	21B00241A	metal	2.48

Center Frequency of Each Channel:

Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)
00	2402	01	2404	02	2406	03	2408
04	2410	05	2412	06	2414	07	2416
08	2418	09	2420	10	2422	11	2424
12	2426	13	2428	14	2430	15	2432
16	2434	17	2436	18	2438	19	2440
20	2442	21	2444	22	2446	23	2448
24	2450	25	2452	26	2454	27	2456
28	2458	29	2460	30	2462	31	2464
32	2466	33	2468	34	2470	35	2472
36	2474	37	2476	38	2478	39	2480

1.2. EUT Information

EUT Power Type	From USB

1.3. Testing Location Information

Testing Location Information			
Test Laboratory：DEKRA Testing and Certification Co., Ltd.			
V	Address	No. 85, Wenlin St., Linkou Dist., New Taipei City 244017, Taiwan, R.O.C.	
	Performed Location	No. 26, Huaya 1st Rd., Guishan Dist.,Taoyuan City 333411, Taiwan, R.O.C.	
	Phone/Fax Number	TEL: +886-3-275-7255	FAX: +886-3-327-8031
	Site Description	Accredited by TAF	
		Accredited Number: 3023	
	Address/ Performed Location	No.372-2, Sec. 4, Zhongxing Rd., Zhudong Township, Hsinchu County 31061, Taiwan, R.O.C.	
	Phone/Fax Number	TEL: +886-3-582-8001	FAX: +886-3-582-8958
	Site Description	Accredited by TAF	
		Accredited Number: 3024	
	Address/ Performed Locatio	No.372, Sec. 4, Zhongxing Rd., Zhudong Township, Hsinchu County 31061, Taiwan, R.O.C.	
	Phone/Fax Number	TEL: +886-3-582-8001	FAX: +886-3-582-8958
	Site Description	Accredited by TAF	
		Accredited Number: 3024	

1.4. Ambient Conditions In The Laboratory

Performed Item	Items	Required	Actual	Test Date	Tested By
RF Conducted Emission	Temperature (°C)	5~35 °C	24.3~26.2 °C	2026/07/17 ~ 2026/07/23	Kevin Lai
	Humidity (%RH)	45~85 %	63.5~67.6 %		

1.5. Measurement Uncertainty

Uncertainties have been calculated according to the DEKRA internal document. The reported expanded uncertainties are based on a standard uncertainty multiplied by a coverage factor of k=2, providing a level of confidence of approximately 95%.

Measurement uncertainties evaluated for each testing system and associated connections are given here to provide the system information for reference. Compliance determinations do not take into account measurement uncertainties for each testing system, but are based on the results of the compliance measurement.

Test item	Uncertainty
Antenna Power, Antenna Power Tolerance and E.I.R.P	Spectrum Analyzer: ±2.13 dB Power Meter: ±1.06 dB
Occupied Bandwidth	±1580.61 Hz
Frequency Tolerance	±1580.61 Hz
Unwanted Emission Strength	±2.13 dB
Secondary Radiated Emission Strength	±2.13 dB
Interference Prevention Function	N/A

1.6. List of Test Equipment

For Conducted Measurements / HY-SR02

	Equipment	Manufacturer	Model No.	Serial No.	Cal. by	Cal. Method	Cal. Date	Due Date
V	DC Power Supply	KEYSIGHT	E36234A	MY59001234	ETC	*(c)	2025/10/27	2026/10/26
V	Spectrum Analyzer	R&S	FSV30	103464	ETC	*(c)	2026/07/08	2027/07/07
V	Power Meter	Anritsu	ML2496A	1947001	ETC	*(c)	2025/12/22	2026/12/21
V	Power Sensor	Anritsu	MA2411B	1911082	ETC	*(c)	2025/12/22	2026/12/21
V	Power Sensor	Anritsu	MA2411B	1911083	ETC	*(c)	2025/12/22	2026/12/21

Note:

1. All equipment is calibrated every year.
2. The test instruments marked with “V” are used to measure the final test results.
3. Test Software Version: DTC_RF_Tool_Release V2.0.115.
4. a) Calibration conducted by the National Institute of Information and Communications Technology(NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
   b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
   c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated agency under Article 102-18 paragraph (1).
   d) Calibration conducted by using other equipment that listed above from a) to c).

2. Test Configuration of EUT

2.1. Test Condition

EUT Operational Condition	
Testing Voltage	DC 5V

2.2. Power Supply Voltage Fluctuation

Voltage Test Item	Test Voltage	Voltage Meter Reading Value
Nominal Voltage	DC 5.0 V	DC 1.8V
Highest Voltage	DC 5.5 V	DC 1.8V
Lowest Voltage	DC 4.5 V	DC 1.8V

Note:

1. The Voltage supply for RF Chip U2 pin C17 is DC 1.8 V.
2. The internal supply gives a fluctuation value less than 1 % (Around 0% from max. to min.)

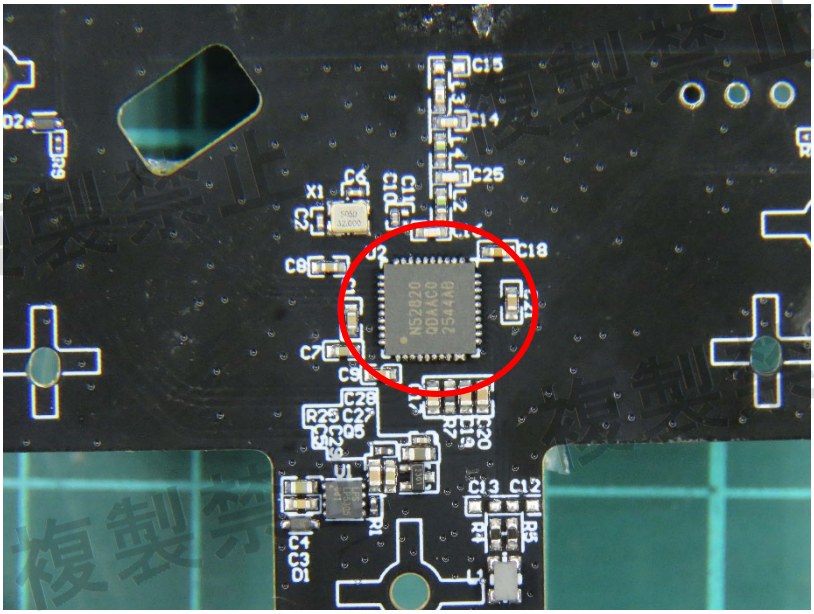
2.3. Test Frequency Mode

Test Software Version	EMI_TEST_TOOL / Version 1.0.9

Modulation or Mode	Frequency (MHz)	Power Setting
GFSK (1 Mbps)	2402	4
	2440	4
	2480	4
GFSK (2 Mbps)	2402	4
	2440	4
	2480	4

2.4. RF and IF Section Must be Tamper Requirement

Requirement	Comments	Result
RF, IF and Modulation section must be tamper	☐Use Special Screw ☐Metal Shielding is Soldered ☒Use Quad Flat Package (QFP) (Please refer to the attachment: EUT Detailed Photographs)	Complete
	☒RF module/Chip pin >10 ☒RF module/Chip pins distance <1.5mm (Please refer to the attachment: EUT Detailed Photographs)	Complete



2.5. Measurement Configuration

Tests Item	Antenna Power, Antenna Power Tolerance and E.I.R.P Occupied Bandwidth Frequency Tolerance Unwanted Emission Strength Secondary Radiated Emission Strength Interference Prevention Function
Test Condition	Conducted measurement at transmit chains

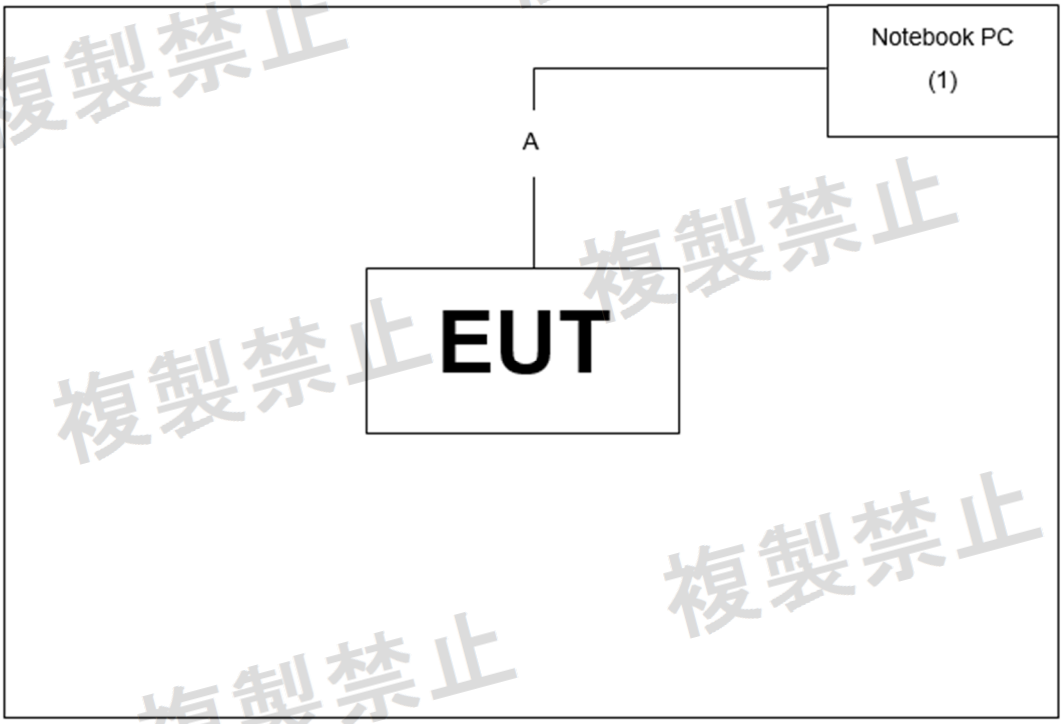
Note:
1. Determining compliance shall be based on the results of the compliance measurement, not taking into account measurement instrumentation uncertainty.
2. After checking the fluctuation of input voltage to the circuit of the radio part (excluding the power supply) of the equipment to be tested, the fluctuation less than +/- 1 % when input voltage from an external supply into the equipment fluctuates +/- 10%, therefore, the test is carried out only at the normal voltage.

2.6. Tested System Details

No.	Equipment	Brand Name	Model No.	Serial No.	Power Cord
1	Notebook PC	DELL	Latitude 5501	4H94P13	N/A

2.7. Configuration of Tested System

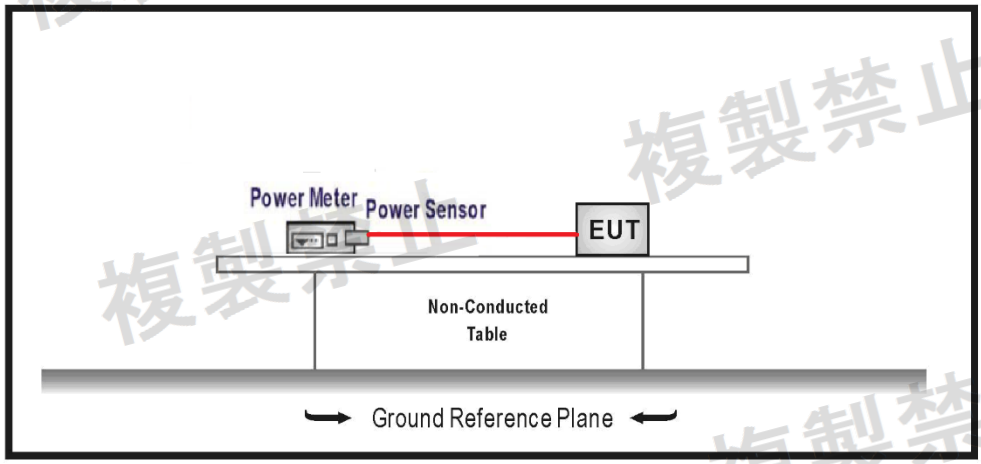
Connection Diagram



	Signal Cable Type	Signal cable Description
A	USB TO USB C Cable	Shielded, 2m

3. Antenna Power, Antenna Power Tolerance and E.I.R.P.

3.1. Test Setup



3.2. Test Limit

Antenna Power: ≦10mW for Other Digital Methods

Antenna Power Tolerance: ≦+20%

EIRP: ≦12.14dBm for Other Digital Methods

3.3. Test Method

According to MIC Notice No. 88 Annex 43.

3.4. Test Procedure

a. Connect a high-frequency power meter to the output of the dummy load (attenuator) and measure the output power.

b. Output power shall be as follows.

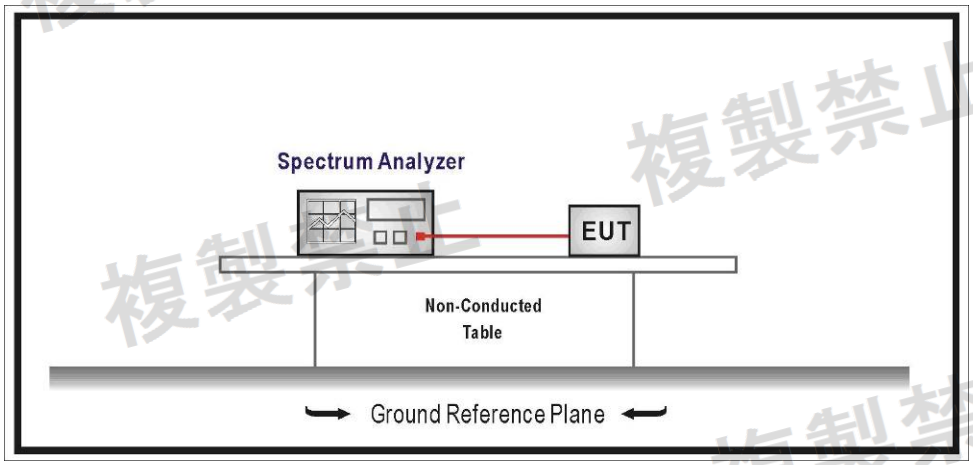
(a) Value of a continuous wave.

3.5. Test Result of Antenna Power, Antenna Power Tolerance and E.I.R.P.

Refer as Appendix A

4. Occupied Bandwidth

4.1. Test Setup



4.2. Test Limit

≦26 MHz for DSSS

4.3. Test Method

According to MIC Notice No. 88 Annex 43.

4.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the modulated transmitter's radio frequency power output.

(a) A positive peak detector function must be used.

(b) A measurement instrument with an integrated 99% power bandwidth function may be used to automate the test process.

(c) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

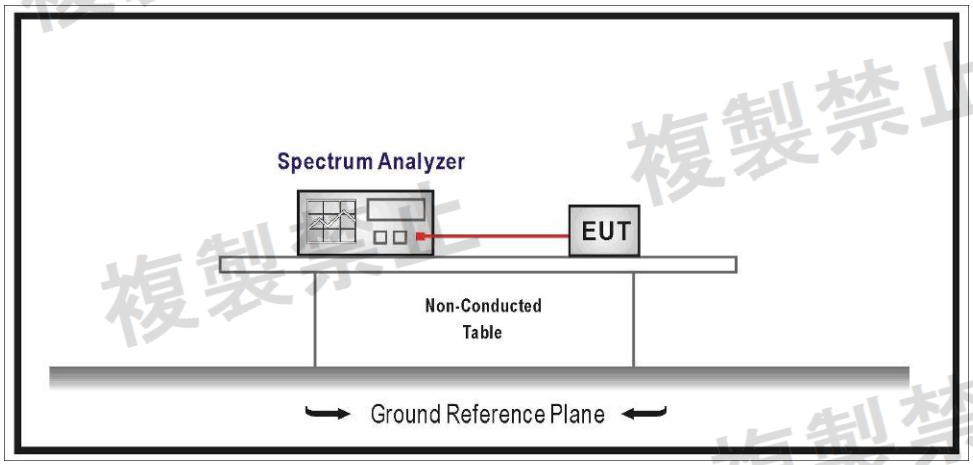
(d) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

4.5. Test Result of Occupied Bandwidth

Refer as Appendix B

5. Frequency Tolerance

5.1. Test Setup



5.2. Test Limit

± 50 ppm

5.3. Test Method

According to MIC Notice No. 88 Annex 43.

5.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the unmodulated or modulated transmitter's radio frequency power output.

(a) A positive peak detector function must be used.

(b) The measurement instrument bandwidth and span must be set sufficiently wide, and the scan time set sufficiently slowly, to ensure all products of the unmodulated signal are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

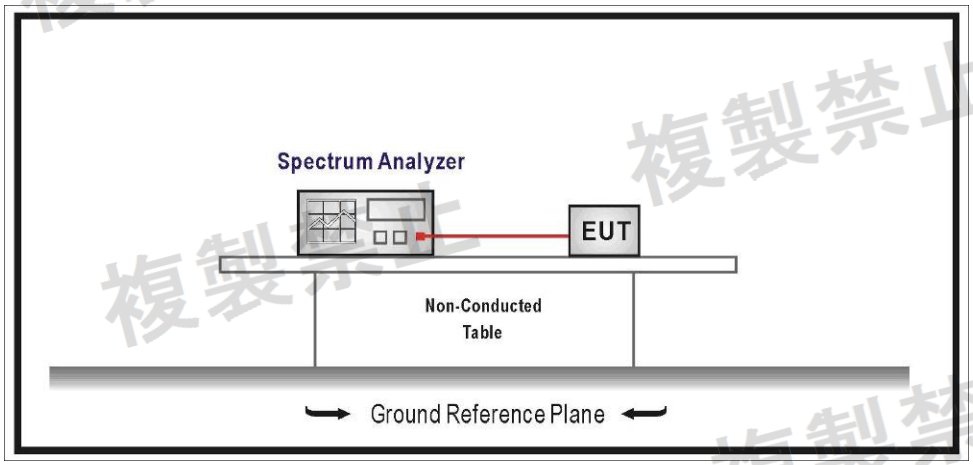
(c) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

5.5. Test Result of Frequency Tolerance

Refer as Appendix C

6. Unwanted Emission Strength

6.1. Test Setup



6.2. Test Limit

≤ 2.5uW/MHz for 30 MHz < f < 2387 MHz

≤ 25uW/MHz for 2387 MHz ≤ f < 2400 MHz

≤ 25uW/MHz for 2483.5 MHz < f ≤ 2496.5 MHz

≤ 2.5uW/MHz for 2496.5 MHz < f < 12500 MHz

6.3. Test Method

According to MIC Notice No. 88 Annex 43.

6.4. Test Procedure

The EUT is connected to the spectrum analyzer and it is configured at maximum output power in the different test channels.

(a) A positive peak detector function must be used.

(b) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slow, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

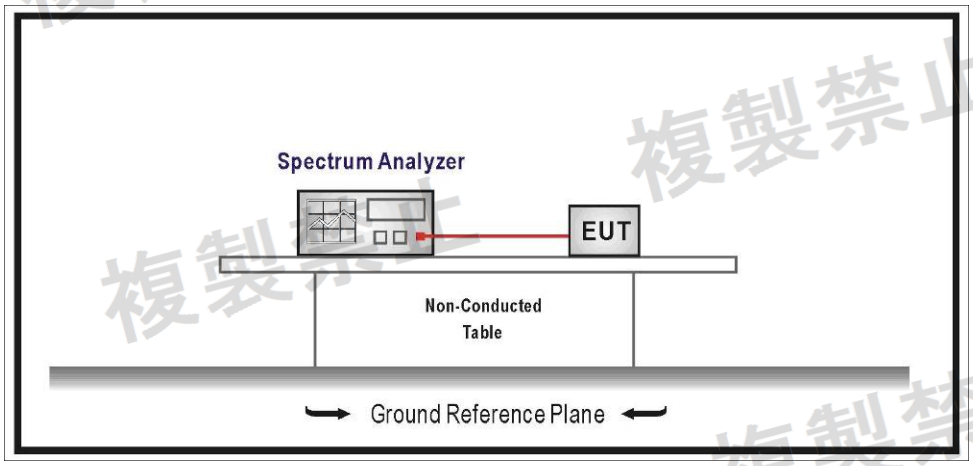
(c) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

6.5. Test Result of Unwanted Emission Strength

Refer as Appendix D

7. Secondary Radiated Emission Strength

7.1. Test Setup



7.2. Test Limit

≤ 4nW for 30 MHz < f < 1000 MHz

≤ 20nW for 1000 MHz ≤ f < 12500 MHz

7.3. Test Method

According to MIC Notice No. 88 Annex 43.

7.4. Test Procedure

The EUT is connected to the spectrum analyzer and it is configured in reception mode in the different test channels.

(a) A positive peak detector function must be used.

(b) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

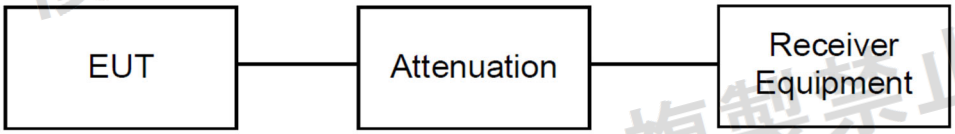
(c) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

7.5. Test Result of Secondary Radiated Emission Strength

Refer as Appendix E

8. Interference Prevention Function

8.1. Test Setup



8.2. Test Method

According to MIC Notice No. 88 Annex 43.

8.3. Test Procedure

Radio equipment used mainly on the same premises and automatically transmits or receives identification code.

8.4. Test Result of Interference Prevention Function

Refer as Appendix F